

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceed the OCM data sheet.

Quality Overview

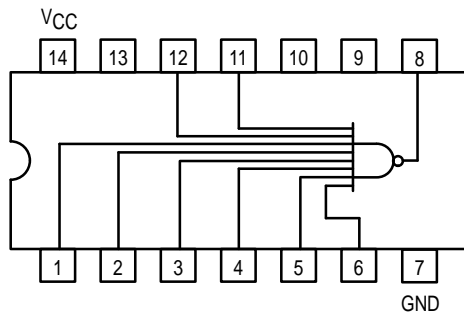
- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-35835
 - Class Q Military
 - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
 - Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

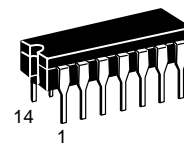


8-INPUT NAND GATE

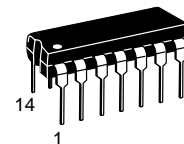


SN54/74LS30

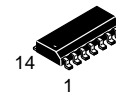
**8-INPUT NAND GATE
LOW POWER SCHOTTKY**



**J SUFFIX
CERAMIC
CASE 632-08**



**N SUFFIX
PLASTIC
CASE 646-06**



**D SUFFIX
SOIC
CASE 751A-02**

ORDERING INFORMATION

SN54LSXXJ Ceramic
SN74LSXXN Plastic
SN74LSXXD SOIC

GUARANTEED OPERATING RANGES

Symbol	Parameter		Min	Typ	Max	Unit
V _{CC}	Supply Voltage	54 74	4.5 4.75	5.0 5.0	5.5 5.25	V
T _A	Operating Ambient Temperature Range	54 74	-55 0	25 25	125 70	°C
I _{OH}	Output Current — High	54, 74			-0.4	mA
I _{OL}	Output Current — Low	54 74			4.0 8.0	mA

SN54/74LS30

DC CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (unless otherwise specified)

Symbol	Parameter		Limits			Unit	Test Conditions
			Min	Typ	Max		
V _{IH}	Input HIGH Voltage		2.0			V	Guaranteed Input HIGH Voltage for All Inputs
V _{IL}	Input LOW Voltage	54			0.7	V	Guaranteed Input LOW Voltage for All Inputs
		74			0.8		
V _{IK}	Input Clamp Diode Voltage			-0.65	-1.5	V	V _{CC} = MIN, I _{IN} = -18 mA
V _{OH}	Output HIGH Voltage	54	2.5	3.5		V	V _{CC} = MIN, I _{OH} = MAX, V _{IN} = V _{IH} or V _{IL} per Truth Table
		74	2.7	3.5		V	
V _{OL}	Output LOW Voltage	54, 74		0.25	0.4	V	I _{OL} = 4.0 mA V _{CC} = V _{CC} MIN, V _{IN} = V _{IL} or V _{IH} per Truth Table
		74		0.35	0.5	V	
I _{IH}	Input HIGH Current				20	μA	V _{CC} = MAX, V _{IN} = 2.7 V
					0.1	mA	V _{CC} = MAX, V _{IN} = 7.0 V
I _{IL}	Input LOW Current				-0.4	mA	V _{CC} = MAX, V _{IN} = 0.4 V
I _{OS}	Short Circuit Current (Note 1)		-20		-100	mA	V _{CC} = MAX
I _{CC}	Power Supply Current Total, Output HIGH				0.5	mA	V _{CC} = MAX
	Power Supply Current Total, Output LOW				1.1		

Note 1: Not more than one output should be shorted at a time, nor for more than 1 second.

AC CHARACTERISTICS (T_A = 25°C)

Symbol	Parameter		Limits			Unit	Test Conditions
			Min	Typ	Max		
t _{PLH}	Turn-Off Delay, Input to Output			8.0	15	ns	V _{CC} = 5.0 V C _L = 15 pF
t _{PHL}	Turn-On Delay, Input to Output			13	20	ns	